Abstract Submitted
for the TSF07 Meeting of
The American Physical Society

Low Level Measurements using the Van der Pauw Technique[1]
MARSHALL PREAS, KUNAL BHATNAGAR, ALEXY VOLKOV, TONI SAUNCY, Angelo State University — As part of the MANDE NSF REU program[1], this project aimed at developing a system to be used for determining electrical resistance in a bulk material or thin film. While a standard two probe technique is sufficient for some low-resistivity samples, the four probe Van der Pauw method is preferred for the materials we wish to study. An automated data acquisition system with geometric corrections was designed utilizing a suite of meters and sources and utilizing LabVIEW^{TM} programming software and GPIB interfacing techniques.

[1]This project supported by the National Science Foundation under grant no. EEC0648761.

Toni Sauncy
Angelo State University

Date submitted: 25 Sep 2007 Electronic form version 1.4